

<b>Notice of References Cited</b>	Application/Control No. 10/534,677		Applicant(s)/Patent Under Reexamination NUYENS ET AL.	
	Examiner Chun-Cheng Wang		Art Unit 4171	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,985,979 A	11-1999	Southwick et al.	524/505
*	B	US-2004/0057988 A1	03-2004	Tsuchida et al.	424/450
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	RU2099974 C1	12-1997	RU	Kornena et al.	A23L 1/24
	O	GB1171068	11-1969	GB	Wirtschaftsprüfungsgesell	C12H 1/06
	P	WO 99/07231	02-1999	US	D'Agostino et al.	A23C 1/00, 9/00, 9/1
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.